## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: Q1/2021 to Q4/2021

Based on structural similarity

| Supplier   |  | User Part Number  |                                   |           |            |           |  |  |
|--|--|---|-----------------------------------|-----------|------------|-----------|--|--|
| Nexperia B.V.<br>Name of Laboratory<br>Assembly reliability labs<br>Based on AEC-Q101 Test |  | PZU16B2L  |                                   |           |            |           |  |  |
|  |  | Part Description  |                                   |           |            |           |  |  |
|  |  | Nexperia DHAM   | Zener                             |           |            |           |  |  |
|  |  | MCD package   |                                   |           |            |           |  |  |
|  |  | Test Conditions   | Duration                          | # Lots    | # Quantity | # Rejects |  |  |
|  | TEST   |   |                                   |           |            |           |  |  |
|  | Pre- and Post-Stress   | T   25.00   |                                   |           |            |           |  |  |
| # E1   | Electrical Test  | Tamb = 25 °C  | N/A                               | see below | all parts  | see below |  |  |
| # A1   | <b>PC</b><br>Preconditioning                                   | JESD22-A113<br>Bake Tamb = 125 °C<br>Soak Tamb = 85 °C, RH = 85%<br>Reflow soldering                | 24 hours<br>168 hours<br>3 cycles | 113       | 9040       | 0         |  |  |
| # B1   | <b>HTRB</b><br>High Temperature Reverse<br>Bias                | MIL-STD-750-1<br>M1038 Method A<br>Tj = Tjmax, Vr = 100% of max. datasheet<br>reverse voltage       | 1000 hours                        | 138       | 11040      | 0         |  |  |
| # B1b  | <b>SSOP</b><br>Steady State Operational                        | MIL-STD-750-1<br>M1038 Method B<br>Tj = Tjmax, Iz = 100% of max. datasheet<br>reverse current       | 1000 hours                        | 20        | 1600       | 0         |  |  |
| # A4   | <b>TC</b><br>Temperature Cycling                               | JESD22-A104<br>-65 °C to Tjmax, not to exceed 150°C   | 1000 cycles                       | 28        | 2240       | 0         |  |  |
| # A3 alt   | <b>AC</b><br>Autoclave   | JESD22-A102<br>Tamb = 121 °C, RH = 100 %<br>Pressure = 205 kPa (29.7 psia)                          | 96 hours                          | 28        | 2240       | 0         |  |  |
| # A2 alt   | <b>H3TRB</b><br>High Humidity High<br>Temperature Reverse Bias | JESD22-A101<br>Tamb = 85 °C, RH = 85%, VR = 80 % of<br>rated reverse voltage <sup>[1]</sup>         | 1000 hours                        | 28        | 2240       | 0         |  |  |
| # A5   | <b>IOL</b><br>Intermittent Operating Life                      | MIL-STD-750 Method 1037 ton = toff, devices powered to insure $\Delta Tj$ = 100 °C for 15000 cycles | 1000 hours                        | 29        | 2320       | 0         |  |  |
| # C8   | <b>RSH</b><br>Resistance to Solder Heat                        | JESD22-A111<br>260 °C ± 5 °C  | 10 s                              | n.a.      | n.a.       | n.a.      |  |  |
| # C10  | <b>SD</b><br>Solderability                                     | J-STD-002   |                                   | 63        | 630        | 0         |  |  |

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Wafer Fab        | Technology | Quantity | Rejects | Failure Rate (FIT) | MTTF (hrs) |
|------------------|------------|----------|---------|--------------------|------------|
| Nexperia<br>DHAM | Zener      | 11040    | 0       | 0.38               | 2.60E+09   |
| 510.01           | Zener      | 11040    | 0       | 0.56               | 2.002+09   |

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